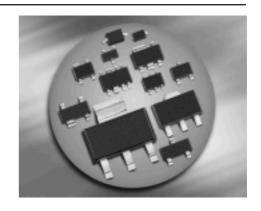


Silicon N-Channel MOSFET Tetrode

- For low noise, high gain controlled input stages up to 1GHz
- Operating voltage 5 V
- Pb-free (RoHS compliant) package
- Qualified according AEC Q101







$\textbf{ESD} \; (\textbf{Electros} tatic \; \textbf{d} is charge) \; sensitive \; device, \; observe \; handling \; precaution!$

Туре	Package	Pin Configuration						Marking
BF2040	SOT143	1=S	2=D	3=G2	4=G1	-	-	NFs
BF2040R	SOT143R	1=D	2=S	3=G1	4=G2	_	-	NFs
BF2040W	SOT343	1=D	2=S	3=G1	4=G2	-	-	NFs

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	8	V
Continuous drain current	I _D	40	mA
Gate 1/ gate 2-source current	±/ _{G1/2SM}	10	
Gate 1 (external biasing)	+V _{G1SE}	7	V
Total power dissipation	P _{tot}		mW
<i>T</i> _S ≤ 76 °C, BF2040, BF2040R		200	
<i>T</i> _S ≤ 94 °C, BF2040W		200	
Storage temperature	$T_{ m stg}$	-55 150	°C
Channel temperature	T _{ch}	150	

Thermal Resistance

Parameter	Symbol	Value	Unit
Channel - soldering point ¹⁾	R_{thchs}		K/W
BF2040, BF2040R		≤ 370	
BF2040W		≤ 280	

 $^{^{1}}$ For calculation of R_{thJA} please refer to Application Note Thermal Resistance



Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics	•		•	•	•
Drain-source breakdown voltage	$V_{(BR)DS}$	10	-	-	V
$I_{\rm D}$ = 20 $\mu {\rm A}$, $V_{\rm G1S}$ = 0 , $V_{\rm G2S}$ = 0					
Gate1-source breakdown voltage	+V _{(BR)G1SS}	6	-	15	
$+I_{G1S} = 10 \text{ mA}, V_{G2S} = 0, V_{DS} = 0$					
Gate2-source breakdown voltage	+V _{(BR)G2SS}	6	-	15	
$+I_{G2S} = 10 \text{ mA}, V_{G1S} = 0, V_{DS} = 0$					
Gate1-source leakage current	+1 _{G1SS}	-	-	50	nA
$V_{\rm G1S} = 5 \text{ V}, V_{\rm G2S} = 0 , V_{\rm DS} = 0$					
Gate2-source leakage current	+1 _{G2SS}	-	-	50	
$V_{\rm G2S} = 5 \text{ V}, \ V_{\rm G1S} = 0 \ , \ V_{\rm DS} = 0$					
Drain current	I _{DSS}	-	-	50	μA
$V_{\rm DS}$ = 5 V, $V_{\rm G1S}$ = 0 , $V_{\rm G2S}$ = 4 V					
Drain-source current	I _{DSX}	-	15	-	mA
$V_{\rm DS}$ = 5 V, $V_{\rm G2S}$ = 4 V, $R_{\rm G1}$ = 100 k Ω					
Gate1-source pinch-off voltage	V _{G1S(p)}	0.3	0.6	-	V
$V_{\rm DS}$ = 5 V, $V_{\rm G2S}$ = 4 V, $I_{\rm D}$ = 20 μA					
Gate2-source pinch-off voltage	V _{G2S(p)}	0.3	0.7		
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 20 μA					

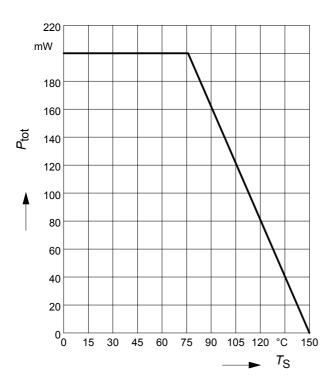


Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
AC Characteristics - (verified by random sar	npling)			•	
Forward transconductance	g _{fs}	37	42	-	mS
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 15 mA, $V_{\rm G2S}$ = 4 V					
Gate1 input capacitance	C _{g1ss}	-	2.9	3.4	pF
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 15 mA, $V_{\rm G2S}$ = 4 V,					
f = 10 MHz					
Output capacitance	C _{dss}	-	1.6	-]
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 15 mA, $V_{\rm G2S}$ = 4 V,					
f = 10 MHz					
Power gain	Gp	20	23	-	dB
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 15 mA, $V_{\rm G2S}$ = 4 V,	"				
f = 800 MHz					
Noise figure	F	-	1.6	2.2	dB
$V_{\rm DS}$ = 5 V, $I_{\rm D}$ = 15 mA, $V_{\rm G2S}$ = 4 V,					
f = 800 MHz					
Gain control range	ΔG_{D}	45	50	-]
$V_{\rm DS}$ = 5 V, $V_{\rm G2S}$ = 40 V , f = 800 GHz					

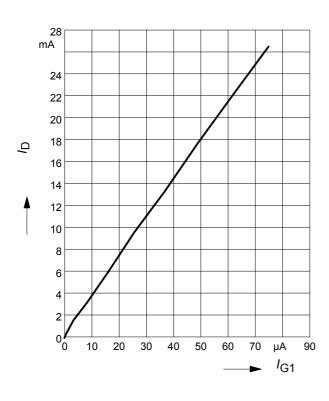


Total power dissipation $P_{tot} = f(T_S)$ BF2040, BFD2040R

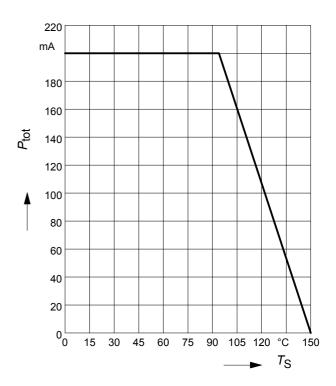


Drain current $I_D = f(I_{G1})$

$$V_{\rm G2S}$$
 = 4V



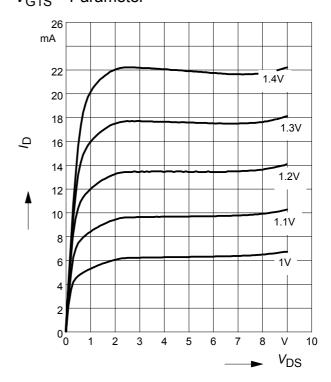
Total power dissipation $P_{tot} = f(T_S)$ BF2040W



Output characteristics $I_D = f(V_{DS})$

$$V_{\rm G2S}$$
 = 4 V

$$V_{\rm G1S}$$
 = Parameter

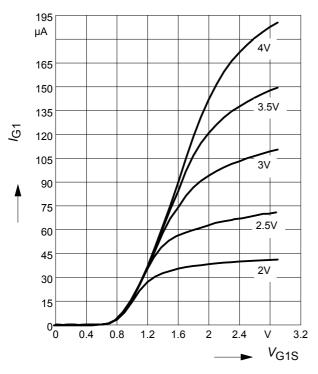




Gate 1 current $I_{G1} = f(V_{G1S})$

 $V_{\rm DS} = 5V$

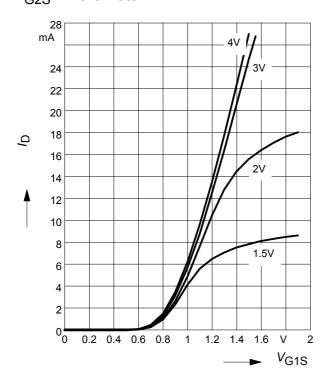
 V_{G2S} = Parameter



Drain current $I_D = f(V_{G1S})$

 $V_{\rm DS} = 5V$

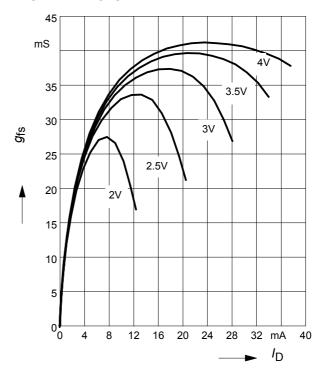
 $V_{\rm G2S}$ = Parameter



Gate 1 forward transconductance

 $g_{fs} = f(I_D)$

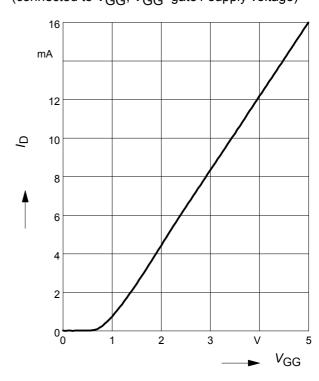
 $V_{\rm DS}$ = 5V, $V_{\rm G2S}$ = Parameter



Drain current $I_D = f(V_{GG})$

 V_{DS} = 5V, V_{G2S} = 4V, R_{G1} = 80k Ω

(connected to V_{GG} , V_{GG} =gate1 supply voltage)

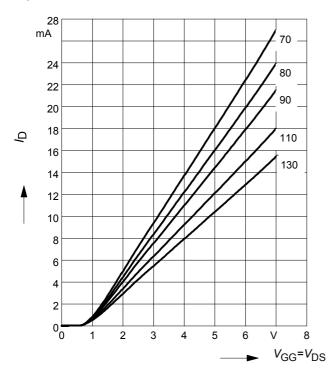




Drain current $I_D = f(V_{GG})$

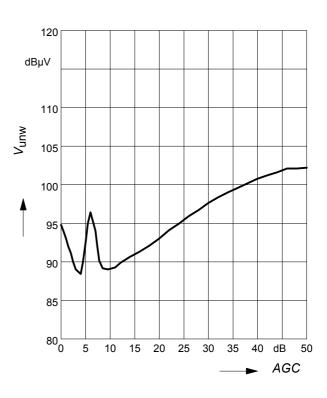
 $V_{\rm G2S}$ = 4V

 R_{G1} = Parameter in $k\Omega$



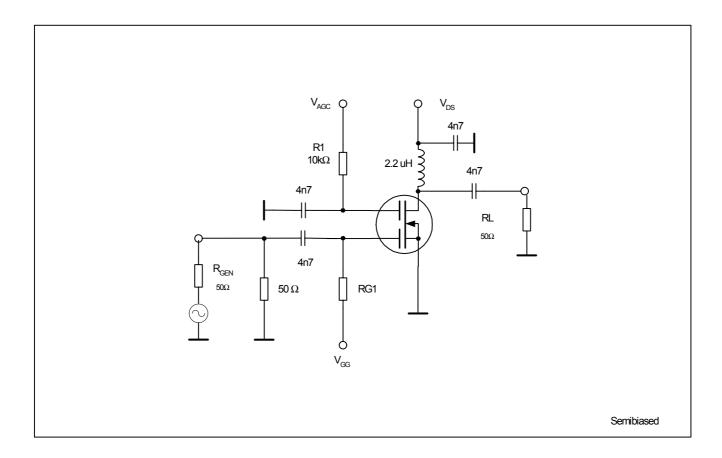
Crossmodulation $V_{unw} = (AGC)$

$$V_{\rm DS}$$
 = 5 V



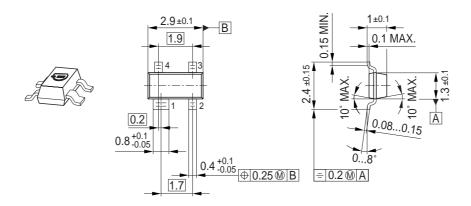


Cossmodulation test circuit

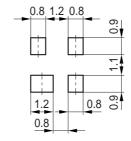




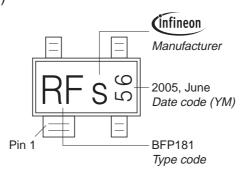
Package Outline



Foot Print

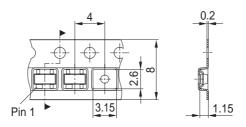


Marking Layout (Example)



Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel

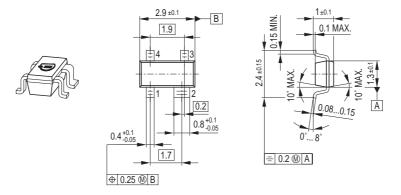


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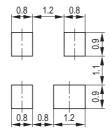
2007-06-01



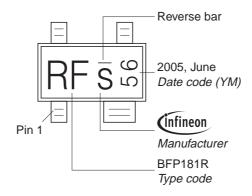
Package Outline



Foot Print

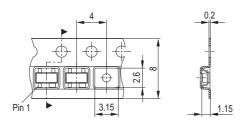


Marking Layout (Example)



Standard Packing

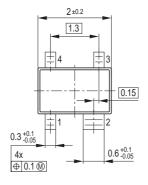
Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel

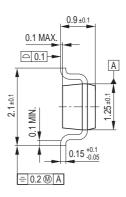




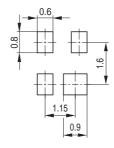
Package Outline



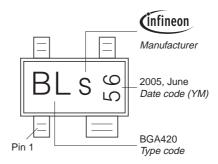




Foot Print

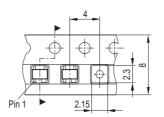


Marking Layout (Example)



Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel







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